TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC7SZ02AFE

2 Input NOR Gate

Features

• High output drive: ±24 mA (typ.)

$$@V_{CC} = 3 V$$

• Super high speed operation: tpD 2.4 ns (typ.)

$$@V_{CC} = 5 \text{ V}, 50 \text{ pF}$$

• Operation voltage range: $V_{CC (opr)} = 1.8 \sim 5.5 \text{ V}$

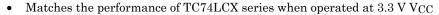
• Supply voltage data retention: $V_{CC} = 1.5 \sim 5.5 \text{ V}$

• Latch-up performance: ±500 mA

ESD performance: Human body model > ±2000 V

Machine model
$$> \pm 200 \text{ V}$$

· Power down protection is provided on all inputs.

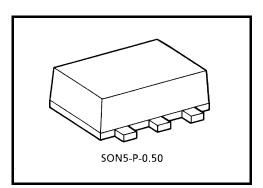


• Input rise and fall time (tr, tf) (recommended operation condition)

$$@V_{CC} = 1.8 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}$$
: 0~20 ns/V

 $@V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V} : 0 \sim 10 \text{ ns/V}$

 $@V_{CC} = 5.5 \text{ V} \pm 0.5 \text{ V}$: $0 \sim 5 \text{ ns/V}$



Weight: 0.003 g (typ.)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~6	V
DC input voltage	V _{IN}	-0.5~6	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V
Input diode current	lıĸ	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±50	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	PD	150	mW
Storage temperature	T _{stg}	-65~150	°C
Lead temperature (10 s)	TL	260	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

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Operating Ranges

Characteristics	Symbol	Rating	Unit
Supply voltage	Voo	1.8~5.5	V
Supply voltage	V _{CC}	1.5~5.5 (Note 1)	V
Input voltage	V _{IN}	0~5.5	V
Output voltage	V _{OUT}	0~V _{CC}	V
Operating temperature	T _{opr}	-40~85	°C
		$0\sim20~(V_{CC}=1.8~V,~2.5~V\pm0.2~V)$	ns/V
Input rise and fall time	dt/dv	$0 \sim 10 \; (V_{CC} = 3.3 \; V \pm 0.3 \; V)$	
		$0~5~(V_{CC} = 5.5~V \pm 0.5~V)$	

Note 1: Data retention only.

Electrical Characteristics

DC Characteristics

	Test Test			Ta = 25°C			Ta = -40~85°C							
Characteristics	Symbol	Circuit		Test Condition	V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit			
High-level input	gh-level input V _{IH} —				1.8	0.75 × V _{CC}	_	_	0.75 × V _{CC}		V			
voltage	VIH			_		0.7 × V _{CC}	_	_	0.7 × V _{CC}		V			
Low-level input					1.8			0.25 × V _{CC}	_	0.25 × V _{CC}	.,			
voltage	V _{IL}			_	2.3- 5.5	_	_	0.3 × V _{CC}	_	0.3 × V _{CC}	V			
					1.8	1.7	1.8	_	1.7					
				I _{OH} = -100 μA	2.3	2.2	2.3	_	2.2					
			V _{IN} = V _{IL}	ΙΟΗ = -100 μΑ	3.0	2.9	3.0	_	2.9		V			
High-level	V _{OH}				4.5	4.4	4.5	_	4.4					
output voltage	VOH			$I_{OH} = -8 \text{ mA}$	2.3	1.9	2.15	_	1.9					
				I _{OH} = -16 mA	3.0	2.4	2.8	_	2.4					
				I _{OH} = -24 mA	3.0	2.3	2.68		2.3	_				
						I _{OH} = -32 mA	4.5	3.8	4.2	_	3.8	_		
			V _{IN} =	I _{OL} = 100 μA	1.8	_	0	0.1	_	0.1				
					2.3	_	0	0.1	—	0.1				
				V _{IN} =	V _{IN} = V _{IH} or	10Ε = 100 μ/ (10Ε = 100 μΑ	3.0	_	0	0.1	_	0.1	
Low-level output	V _{OL}						4.5	—	0	0.1	—	0.1	V	
voltage	ltage VOL —		VIL	I _{OL} = 8 mA	2.3	_	0.1	0.3	—	0.3	3			
				I _{OL} = 16 mA	3.0	_	0.15	0.4	—	0.4				
			I _{OL} = 24 mA	3.0	_	0.22	0.55	—	0.55					
			I _{OL} = 32 mA	4.5	_	0.22	0.55	_	0.55					
Input leakage current	I _{IN}	_	V _{IN} = 5.5	V or GND	0- 5.5			±1	_	±10	μΑ			
Quiescent supply current	Icc	_	$V_{IN} = V_{C}$	_C or GND	5.5	_	_	2	_	20	μΑ			

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AC Characteristics (input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test	Test Condition		Ta = 25°C			Ta = -4	Unit	
Characteristics	Characteristics Symbol Circui	Circuit	t lest Condition	V _{CC} (V)	Min	Тур.	Max	Min	Max	Offic
				1.8	2.0	4.4	9.5	2.0	10.0	
Propagation delay tPLH time tPHL	_	$C_L = 15 \text{ pF},$ $R_L = 1 \text{ M}\Omega$	2.5 ± 0.2	8.0	2.9	6.5	0.8	7.0	ns ns	
			3.3 ± 0.3	0.5	2.3	4.5	0.5	4.7		
			5.0 ± 0.5	0.5	1.9	3.9	0.5	4.1		
			$\begin{aligned} C_L &= 50 \text{ pF}, \\ R_L &= 500 \ \Omega \end{aligned}$	3.3 ± 0.3	1.5	2.9	5.0	1.5	5.2	
				5.0 ± 0.5	0.8	2.4	4.3	0.8	4.5	
Input capacitance	C _{IN}	_	_	0-5.5	_	4	_	_		pF
Power dissipation capacitance C	Coo		(Note)	3.3	_	19				pF
	CPD	C _{PD} —		5.5	_	27				

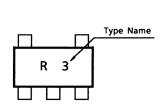
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

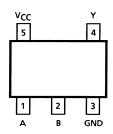
Average operating current can be obtained by the equation.

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Marking

Pin Assignment (top view)



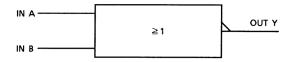


Truth Table

Α	В	Y
L	L	Н
L	Н	L
Н	L	L
Н	Н	L

Logic Diagram

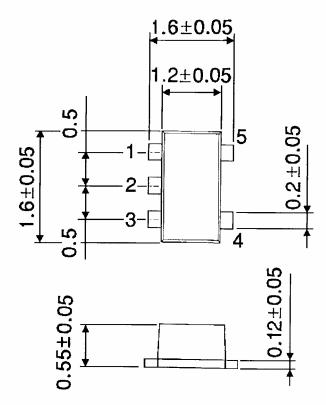
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TC7SZ02AFE

Package Dimensions

SON5-P-0.50 Unit: mm



Weight: 0.003 g (typ.)

2007-11-01

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RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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